



TTEP 2026

TEST TECHNOLOGY EDUCATIONAL PROGRAM 2026

Call for Tutorial Proposals

(ITC-India, ITC, ITC-Asia, ATS, and LATS)

The Tutorials & Education Group (TEG) of the IEEE Computer Society Test Technology Technical Council (TTTC) organizes in 2026 a comprehensive set of Test Technology Tutorials to be held in conjunction with TTTC-sponsored technical meetings. The objective of this common call is to invite submissions for tutorial proposals to enable the selection of the best-fitted tutorials for each technical meeting as part of the annual Test Technology Educational Program (TTEP).

The tutorials accepted by the Program Committee will be included in the Test Technology Educational Program, intending to serve the test and design professionals offering fundamental education and expert knowledge in state-of-the-art test technology topics.

Participation in TTEP-organized tutorials is *accredited* by the Test Technology Technical Council. Each full-day tutorial corresponds to four TTEP units (half-day tutorial corresponds to two TTEP units). Upon completion of every sixteen units official accreditation in the form of the “IEEE TTTC Test Technology Certificate” is presented to the participants.

The TTEP 2026 tutorials program includes (but is not limited to) the following technical meetings:

- **International Test Conference – India (ITC-India’26)**
- **International Test Conference (ITC’26)**
- **International Test Conference – Asia (ITC-Asia’25)**
- **Asian Test Symposium (ATS’26)**
- **Latin American Test Symposium (LATS’26)**

TTEP accommodates a wide range of technical areas, from mature test topics of high interest to industrial test engineers to emerging test topics with an emphasis on novelty. TTEP is soliciting new and updated tutorial proposals, as well as proposals for Test Clinics, which are particularly geared towards newcomers to the area of testing, such as new test engineers and students pursuing graduate studies in testing, with an objective of offering a broad yet comprehensive review of basic test topics in an accessible way to the lay audience. The topics of interest for the year 2026 TTEP Tutorials include (but are not limited to):

- 3D chiplet testing
- Artificial Intelligence for test
- Automatic test equipment
- Board-level testing
- Built-in self-test (BIST)
- Data analytics
- Defect oriented testing
- Design for testability
- Diagnosis and debug
- Embedded core testing
- Failure analysis techniques
- Functional safety
- High-speed interface testing
- Memory testing
- Mixed-Signal/Analog testing
- Nanometer technology testing
- On-line and In-field testing
- Performance/Delay testing
- Microprocessor testing
- Power issues in testing
- Reliability and automotive testing
- Secure DFT
- System-level testing
- Test economics
- Test resource partitioning
- Test related standards
- Testing machine learning engines
- Verification and validation
- Wafer testing
- Yield optimization and test

Submissions: All tutorial proposal submissions to TTEP 2026 are to be made electronically (in PDF format using the TTEP tutorial proposal template provided on both the TTEP main website and the submission website) through the TTEP submissions website:

<http://ttep.tttc-events.org/ttep/submission.html>

Deadline for tutorial proposals: March 15th, 2026.

Contact Information:

TTEP Chair:

Riccardo Cantoro, Politecnico di Torino, IT

E: riccardo.cantoro@polito.it

TTEP Program Chair:

Giusy Iaria, Politecnico di Torino, IT

E: giusy.iaria@polito.it

TTTC Liaison:

Yervant Zorian, Synopsys, US

E: yervant.zorian@synopsys.com

TTEP central web site: <http://ttep.tttc-events.org/ttep/>

TTEP web site for submissions: <http://ttep.tttc-events.org/ttep/submission.html>